

71-76GHz Medium Power Amplifier

GaAs Monolithic Microwave IC

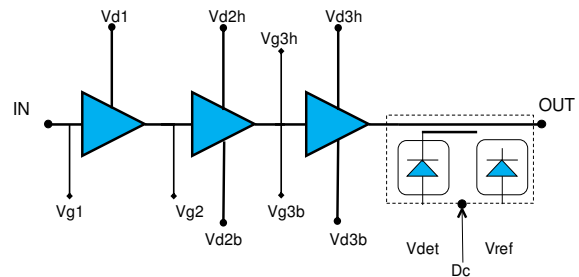
Description

The CHA3080-98F is a three-stage monolithic Medium Power Amplifier. This circuit includes a power detector which integrates a directional coupler, a detection diode and a reference diode to be used in differential mode.

It is dedicated to E-band telecommunication, particularly well suited for the new generation of high capacity Backhaul.

The circuit is manufactured with a pHEMT process, 0.1 μ m gate length, via holes through the substrate, air bridges and electron beam gate lithography.

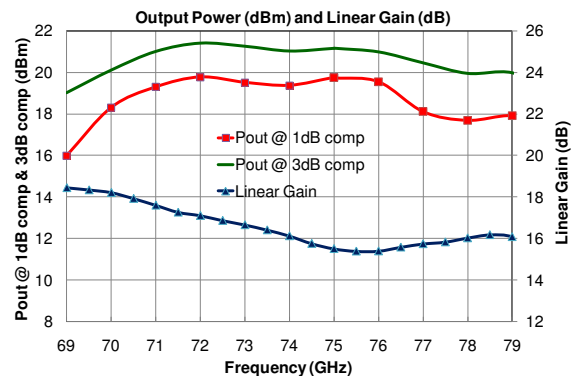
It is available in chip form with BCB layer protection.



Functional diagram

Main Features

- Broadband performances: 71-76GHz
- 16dB linear gain
- 19dBm power at 1dB compression
- 20dB power detector dynamic range
- BCB layer protection
- DC bias: Vd=3.5V@Id=280mA
- Chip size 3.96x1.78x0.07mm



Main Electrical Characteristics

Tamb.= +25 °C

Symbol	Parameter	Min	Typ	Max	Unit
Freq	Frequency range	71		76	GHz
Gain	Linear Gain		16		dB
P1dB	Output Power @1dB comp.		19		dBm
Psat	Saturated Output Power		21		dBm
Dr	Detection dynamic range (for output power detection up to Psat)		20		dB

Electrical Characteristics

T_{amb.} = +25°C, V_d = Dc = 3.5V, I_d (quiescent) = 280mA

Symbol	Parameter	Min	Typ	Max	Unit
Freq	Frequency range	71		76	GHz
Gain	Linear Gain		16		dB
P1dB	Output power @ 1dB compression		19		dBm
Psat	Saturated Output Power		21		dBm
Dr	Detection dynamic range (for output power detection up to Psat)		20		dB
Vdetect	Voltage detection V _{ref} -V _{det} up to Psat		50 to 1400		mV
RLin	Input Return Loss		12		dB
RLout	Output Return Loss		12		dB
Gain ctrl	Gain control range with V _{g1} &V _{g2} tuning (with V _d fixed at 3.5V)		10		dB
NF	Noise Figure		4.0		dB
V _{d1} , V _{d2h} , V _{d3h} , V _{d2b} , V _{d3b}	Drain supply voltage		3.5		V
I _d	Supply quiescent current		280		mA
V _{g1} , V _{g2} , V _{g3b} , V _{g3h}	Gate supply voltage		0.15		V
Dc	Detector supply voltage		3.5		V
IDc	Detector bias current		240		μA

These values are representative of on-wafer measurements that are made without bonding wires at the RF ports but with 10kΩ resistor in parallel on pads V_{det} and V_{ref}.

A ribbon (75μm wide) connection at the input and the output of the MMIC amplifier (See chapter recommended chip assembly) should improve the performances.

Absolute Maximum Ratings ⁽¹⁾

T_{amb.} = +25°C

Symbol	Parameter	Values	Unit
V _d	Drain bias voltage	4V	V
I _d	Drain bias current	350	mA
V _g	Gate bias voltage	-2 to +0.4	V
P _{in}	Maximum continuous input power	+12	dBm
T _j	Junction temperature	175	°C
T _a	Operating temperature range	-40 to +85	°C
T _{stg}	Storage temperature range	-55 to +150	°C

⁽¹⁾ Operation of this device above any one of these parameters may cause permanent damage.

Typical on-wafer Sij parameters

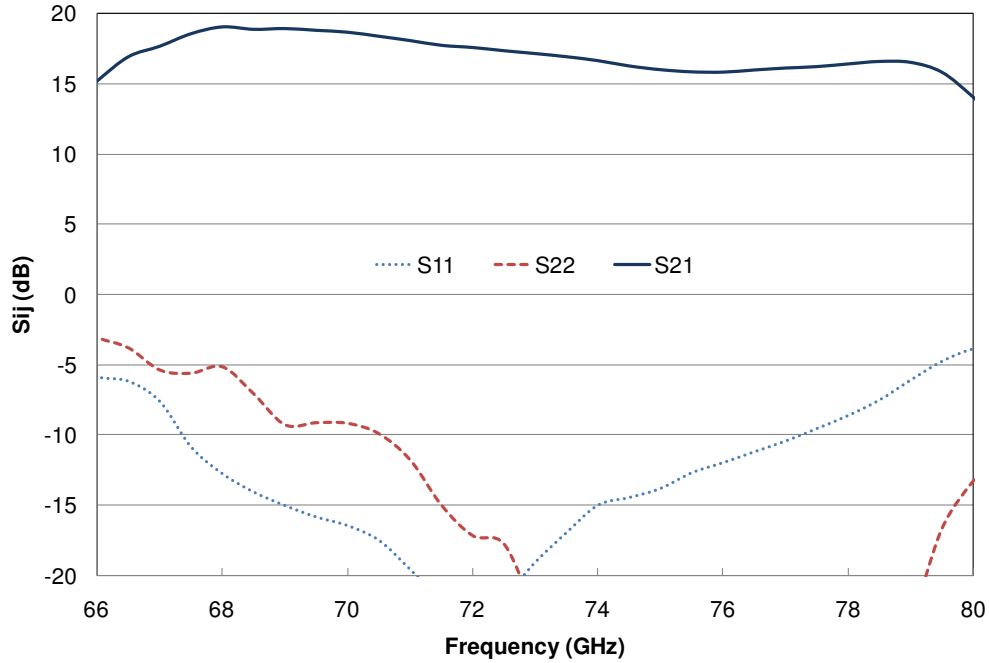
Tamb.= +25°C, Vd = Dc = 3.5V, Id (quiescent) = 280mA

Freq (GHz)	S11 (dB)	PhS11 (°)	S21 (dB)	PhS21 (°)	S12 (dB)	PhS12 (°)	S22 (dB)	PhS22 (°)
55	-2.46	132.0	-18.06	88.2	-38.27	-59.1	-3.1	154.1
56	-2.15	130.4	-14.57	64.0	-46.79	-110.3	-3.86	136.3
57	-2.08	124.3	-10.74	45.9	-47	-90.7	-5.15	120.0
58	-2.11	117.7	-6.58	16.0	-56.14	173.2	-8.11	96.1
59	-2.24	109.3	-3.93	-17.5	-48.75	-83.7	-13.05	55.6
60	-2.46	100.8	-1.3	-49.8	-44.01	179.0	-18.18	-34.7
61	-2.70	93.3	1.51	-84.4	-47.31	-144.5	-12.31	-109.5
62	-2.97	80.9	3.03	-112.9	-48.68	-148.7	-8.32	-135.7
63	-3.10	59.9	5.28	-144.3	-44.74	147.4	-6.44	-155.0
64	-4.00	37.4	7.81	-176.8	-58.68	41.4	-5.04	-175.9
65	-4.79	13.9	11.13	151.2	-46.69	-106.8	-4.4	168.1
66	-5.95	-3.8	14.36	111.5	-43.75	-70.0	-2.98	154.8
67	-7.25	-50.7	16.74	61.9	-39.35	-109.3	-5.84	114.3
68	-12.65	-125.9	18.02	5.0	-37.08	-155.6	-5.06	95.4
69	-15.54	167.5	17.96	-44.2	-36.92	165.9	-9.55	81.9
70	-18.12	116.8	17.84	-89.5	-37.08	130.1	-8.88	53.1
71	-21.43	105.4	17.31	-132.3	-37.51	95.1	-11.49	30.3
72	-23.63	138.6	16.86	-172.1	-38.17	56.3	-16.38	-29.7
73	-18.57	150.3	16.32	145.1	-39.03	15.9	-20.6	-72.6
74	-14.93	142.7	15.79	104.0	-39.58	-22.7	-25.62	-167.6
75	-14.01	124.4	15.19	66.1	-40.28	-58.2	-24.88	140.9
76	-11.98	115.7	15.05	29.2	-39.71	-96.2	-25.01	38.3
77	-10.37	102.9	15.43	-12.2	-39.19	-135.3	-24.05	21.1
78	-8.42	88.3	15.76	-59.2	-38.74	-176.8	-23.41	-22.1
79	-5.87	68.3	15.85	-114.1	-38.67	135.9	-24.16	37.4
80	-4.00	36.6	13.32	-178.6	-40.65	81.3	-13.51	21.1
81	-4.09	0.4	8.78	127.1	-45.06	31.7	-9.22	-24.3
82	-5.32	-27.5	3.04	83.7	-50.27	-31.9	-7.24	-49.4
83	-6.17	-53.8	-1.89	53.5	-52.02	-136.3	-6.7	-73.0
84	-7.18	-76.6	-6.21	26.8	-51.33	149.9	-6.31	-91.1
85	-8.67	-97.1	-10.46	5.8	-52.71	100.1	-6.34	-105.9
86	-9.94	-116.1	-13.65	-12.5	-52.42	90.9	-6.78	-115.8
87	-11.29	-131.7	-15.77	-35.6	-50.5	36.0	-6.32	-126.7
88	-12.33	-148.4	-18.17	-56.9	-48.64	-30.4	-6.31	-138.3
89	-13.22	-162.5	-19.99	-81.0	-49.99	-117.4	-6.47	-150.8
90	-13.92	-175.1	-21.67	-109.9	-49.76	179.0	-6.82	-164.2
91	-14.52	169.6	-23.45	-140.9	-48.91	148.2	-7.47	-178.6
92	-15.11	154.1	-25.76	-174.2	-48.04	113.4	-8.69	163.1
93	-14.60	141.8	-28.46	151.7	-47.25	86.4	-10.51	136.2
94	-13.52	125.1	-30.15	119.1	-43.54	74.3	-14.36	83.5
95	-12.99	102.5	-30.87	49.4	-36.3	6.8	-14.84	-18.6

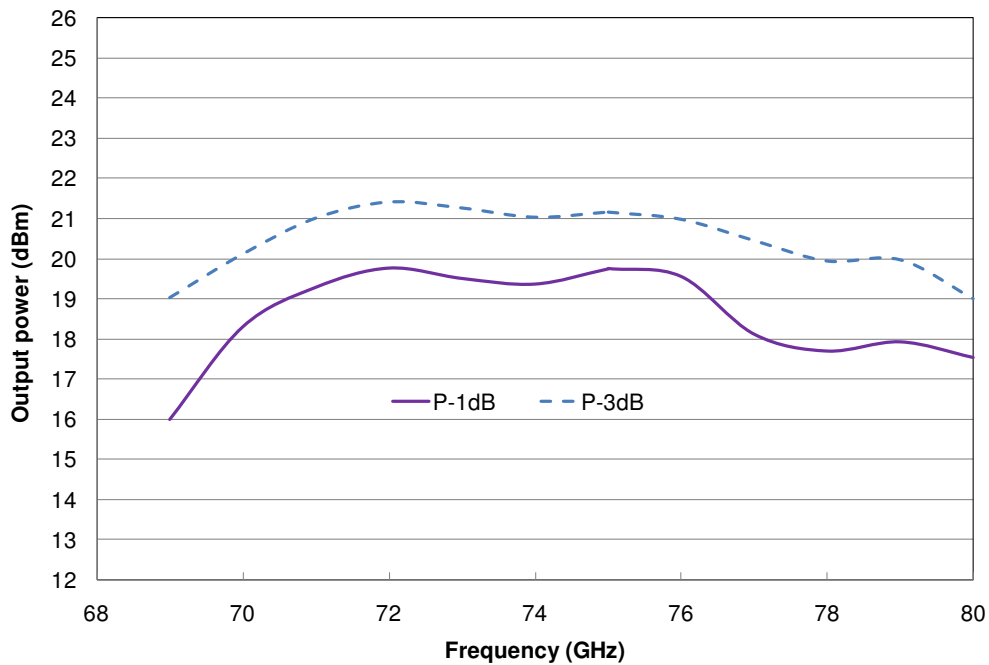
Typical on wafer Measurements

Tamb.= +25°C, Vd = Dc = 3.5V, Id (quiescent) = 280mA

Gain & Return loss versus frequency



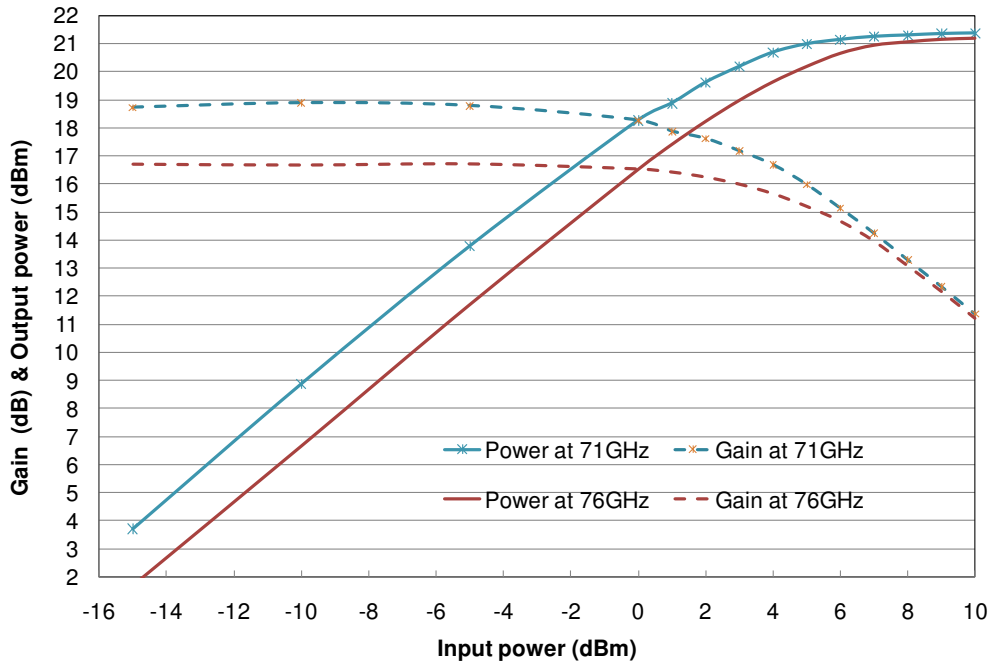
Output power at 1 & 3 dB compression



Typical on wafer Measurements

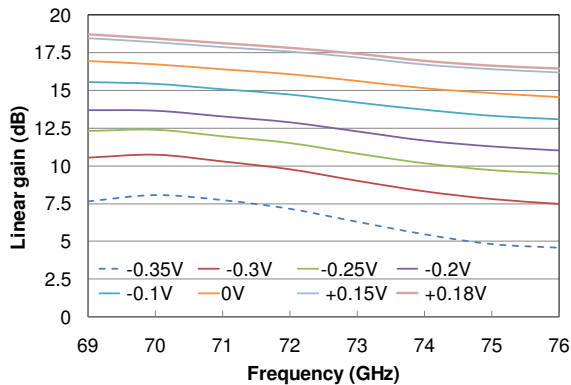
Tamb.= +25°C, Vd = Dc = 3.5V, Id (quiescent) = 280mA

Gain & output power versus input power



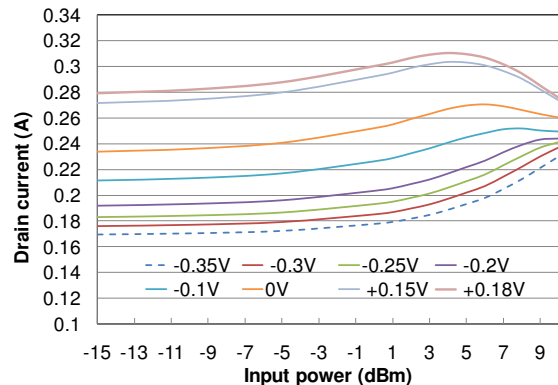
Linear Gain versus gate voltage

Vg3 fixed at +0.18V, Vg1=Vg2 variable



Drain current versus gate voltage & Pin

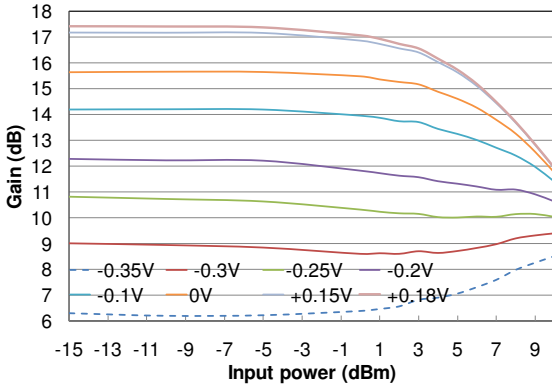
Vg3 fixed at +0.18V, Vg1=Vg2 variable



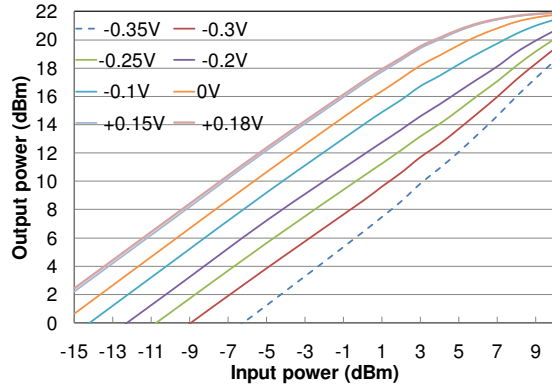
Typical on wafer Measurements

Tamb.= +25°C, Vd = Dc = 3.5V, Id (quiescent) = 280mA

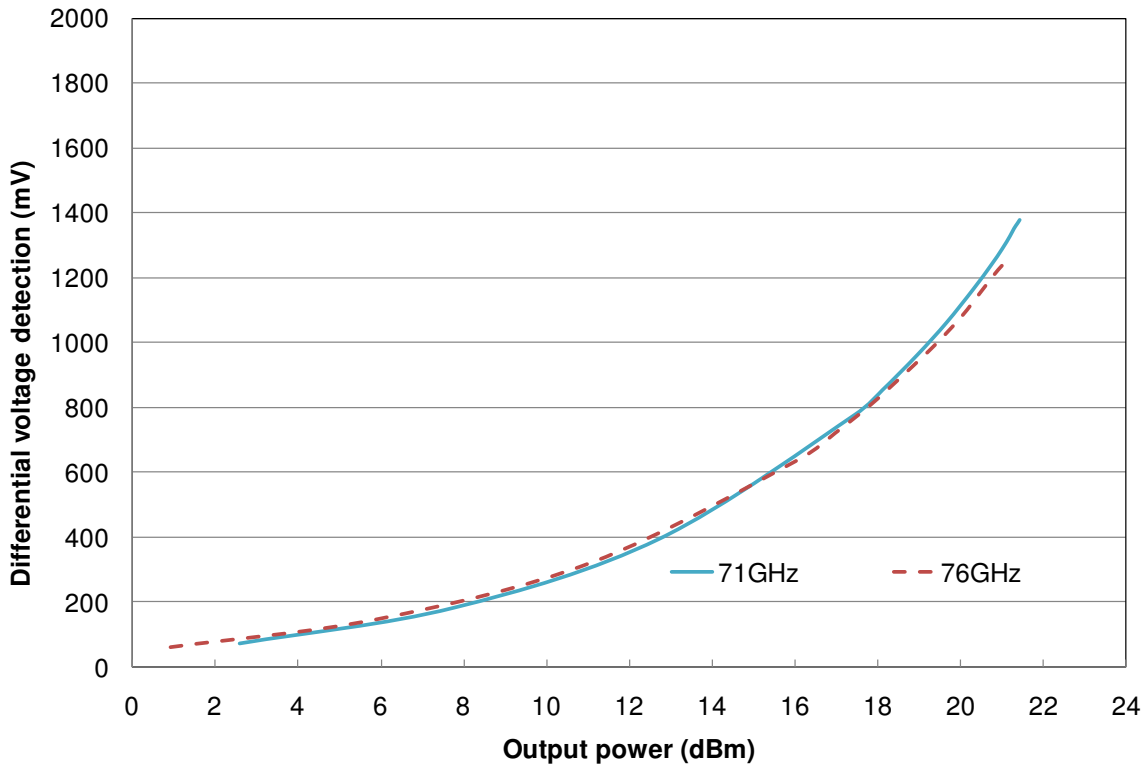
Gain vs input power & gate voltage



Pout vs input power & gate voltage



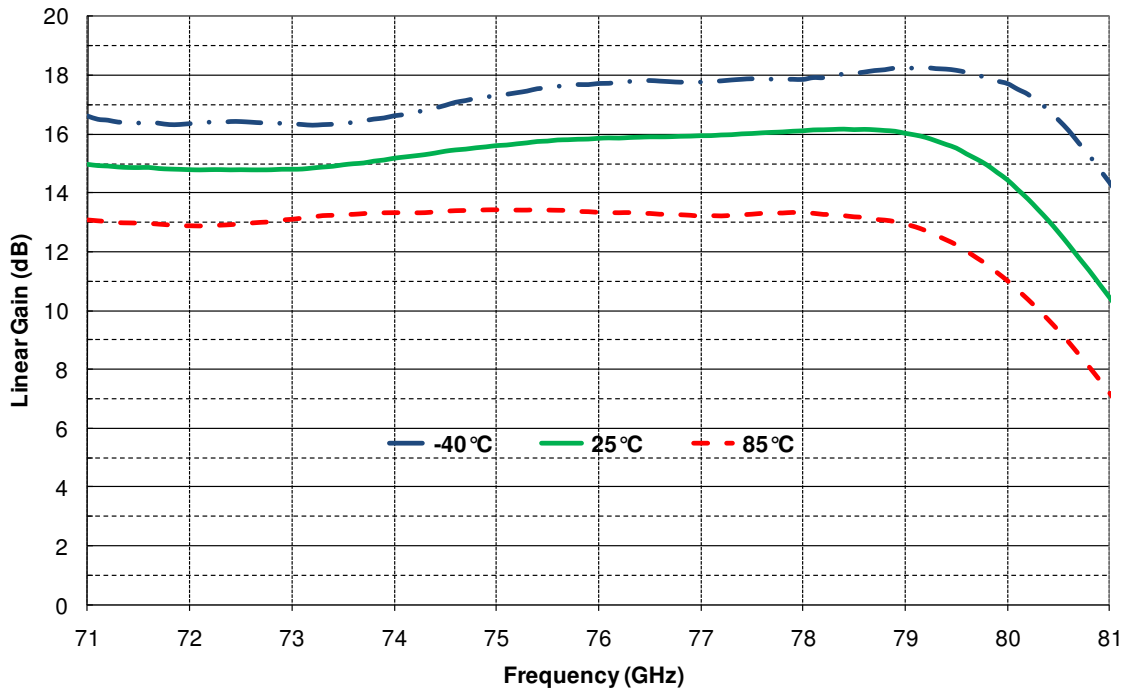
Power detection versus output power
Differential voltage



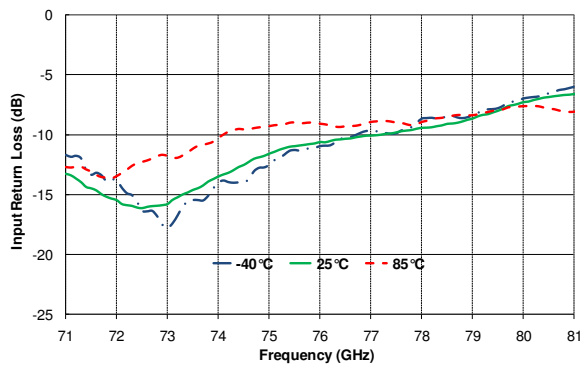
Typical Test Fixture Measurements

Tamb.= -40°C / +25°C / +85°C, Vd = +3.5V, Vg = +0.15V
 Id= 340 mA @ -40°C / 280 mA @ +25°C / 250mA @ +85°C
 Measurements are given in the test fixture access plans

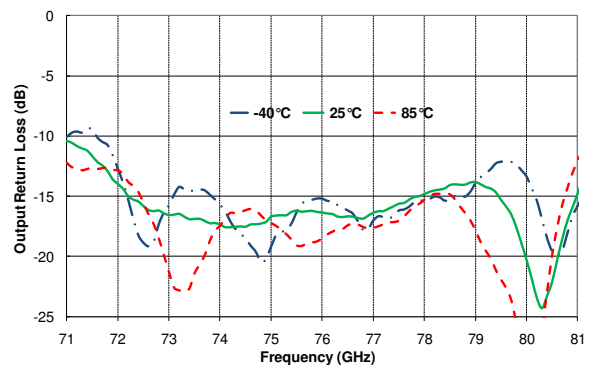
Linear Gain versus Temperature



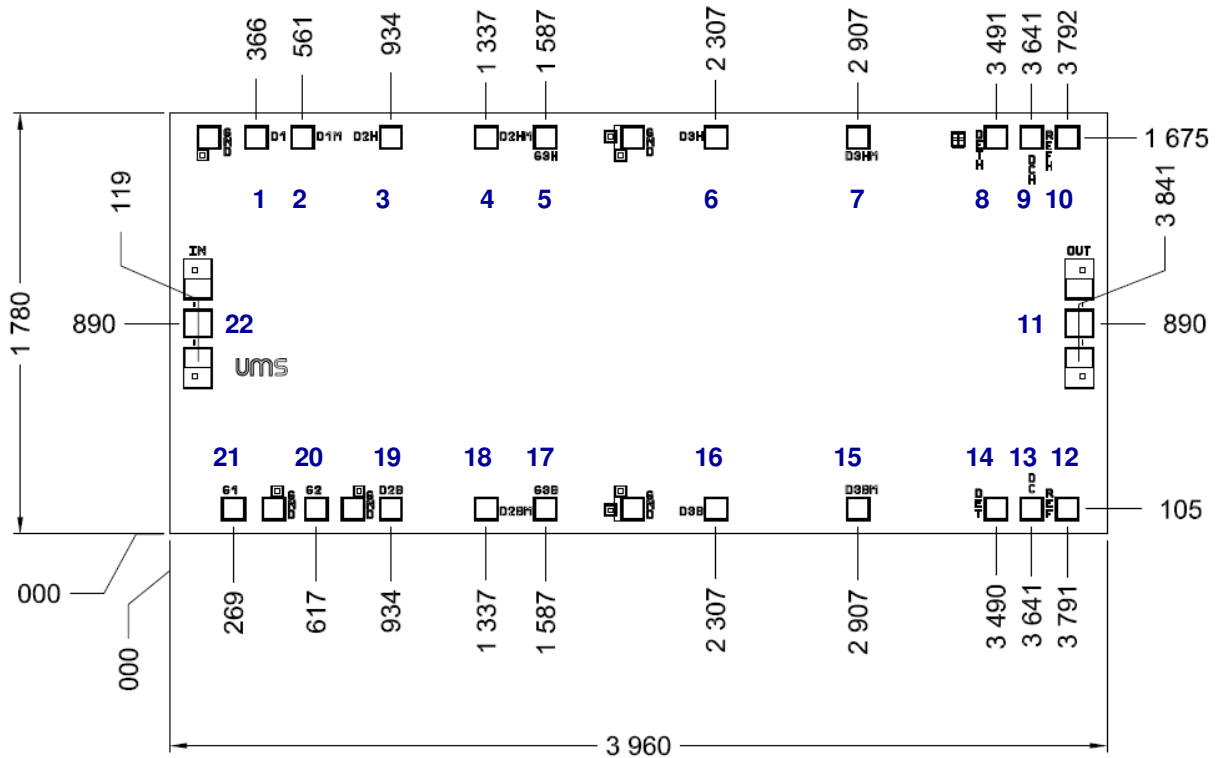
Input Return Loss versus Temperature



Output Return Loss versus Temperature



Mechanical data



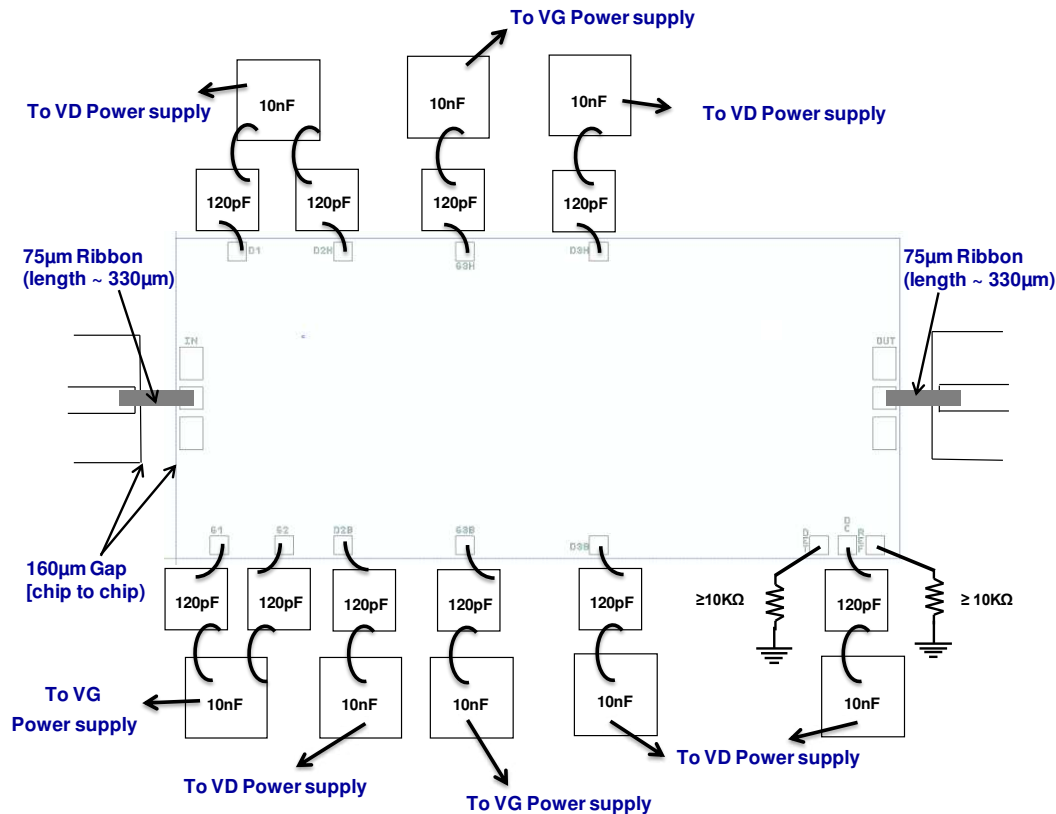
Chip thickness: 70µm.
 Chip size: 3960x1780 ±35µm
 All dimensions are in micrometers

RF Pads = 108 x 106 (BCB opening)
 DC Pads = 86 x 83 (BCB opening)

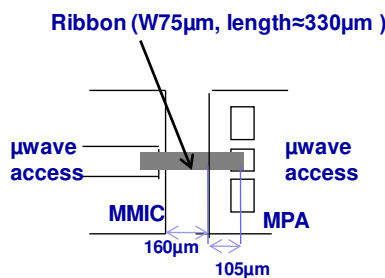
Recommended circuit bonding table

Pad number	Pad name	Description
1, 3, 6	D1; D2H; D3H	Drain voltage (3.5V, 160mA)
16, 19	D3B, D2B	Drain voltage (3.5V, 120mA)
5	G3H	Gate voltage (0.15V)
17, 20, 21	G3B, G2, G1	Gate voltage (0.15V)
14	DET	Detector output
12	REF	Detector reference output
13	DC	DC voltage detector (3.5V, 240 μ A)
22	IN	RF in
11	OUT	RF out
2, 4, 7	D1M; D2HM; D3HM	Not connected
15, 18	D3BM, D2BM	Not connected
8, 9, 10	DETH, DCH, REFH	Not connected
	GND	Not connected

Recommended assembly plan



The design of the circuit integrates a half ribbon (75µm wide) connection at the input and the output of the MMIC amplifier compliant with a 50 Ohm line on GaAs MMIC. The circuits have to be as close as possible to each other; the ribbon length must be as short as possible: typically 160µm gap between two chips is considered, and the loop height must also be the smallest possible (80µm).

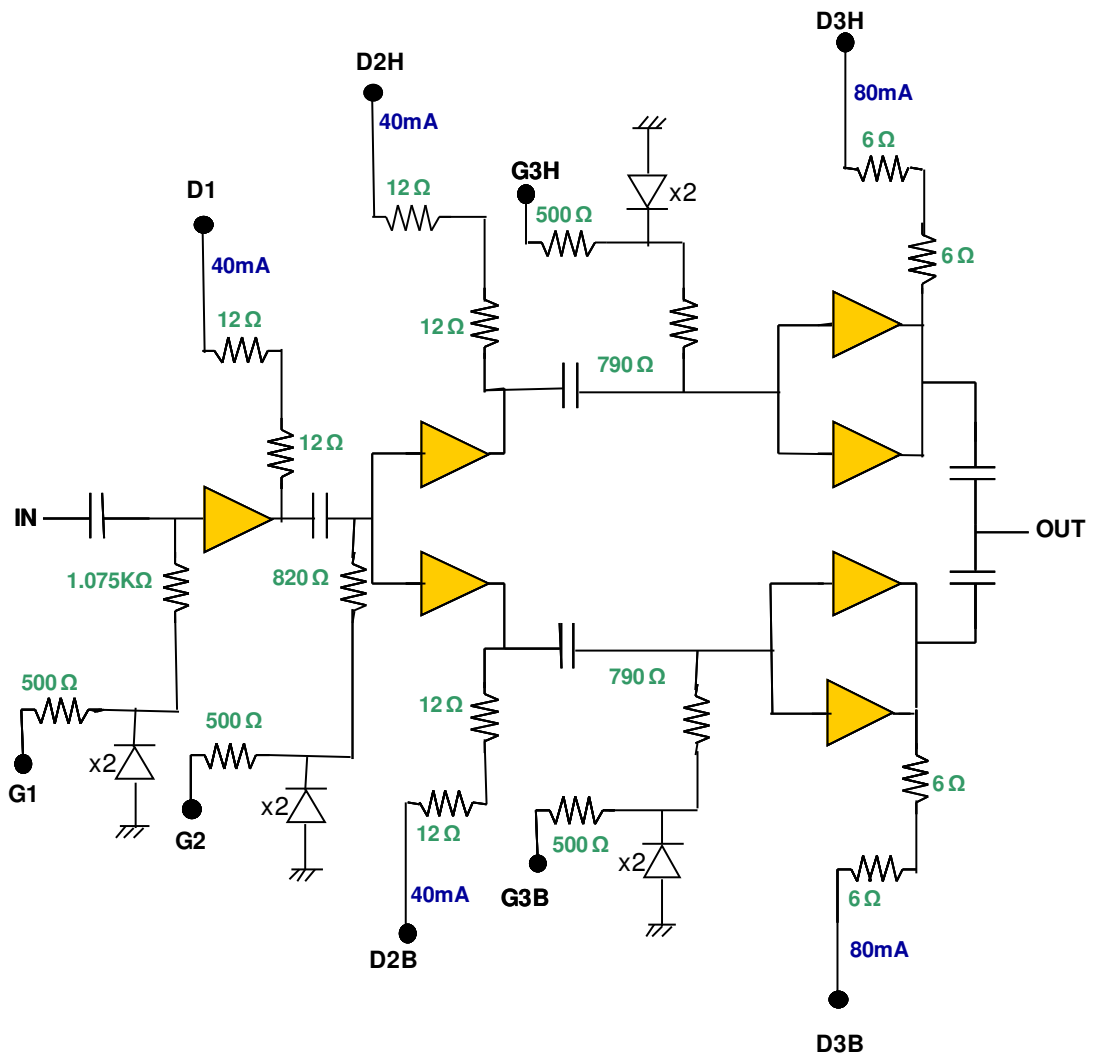


A second solution is to use wires ($\varnothing 25\mu\text{m}$). In this case a minimum of two wires together with the same chip to chip distance mention above are necessary to reduce the inductance effect. Nevertheless, simulations show an improvement of RF performance for E-band frequency range with the use of ribbon connection instead of wire.

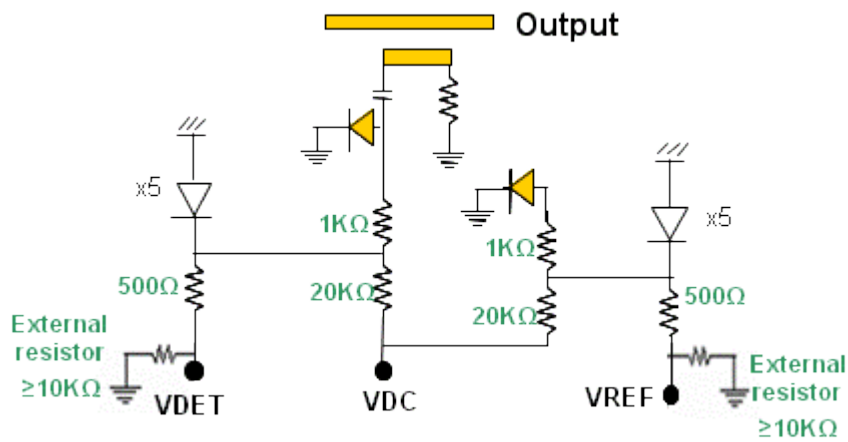
For DC connection (DC pads), a 25µm bonding is preferred. Due to BCB coating on the chip, qualification domain requires the chip to be glued.

DC Schematic

3.5V, 280mA



Detector



Recommended ESD management

Refer to the application note AN0020 available at <http://www.ums-gaas.com> for ESD sensitivity and handling recommendations for the UMS products.

Recommended environmental management

UMS products are compliant with the regulation in particular with the directives RoHS N°2011/65 and REACH N°1907/2006. More environmental data are available in the application note AN0019 also available at <http://www.ums-gaas.com>.

Ordering Information

Chip form:

CHA3080-98F/00

Information furnished is believed to be accurate and reliable. However **United Monolithic Semiconductors S.A.S.** assumes no responsibility for the consequences of use of such information nor for any infringement of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of **United Monolithic Semiconductors S.A.S.** Specifications mentioned in this publication are subject to change without notice. This publication supersedes and replaces all information previously supplied. **United Monolithic Semiconductors S.A.S.** products are not authorised for use as critical components in life support devices or systems without express written approval from **United Monolithic Semiconductors S.A.S.**